

ECE 340 Lecture 13

Semiconductor Electronics

Spring 2022

10:00-10:50am

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2062 ECE Building

Today's Discussion

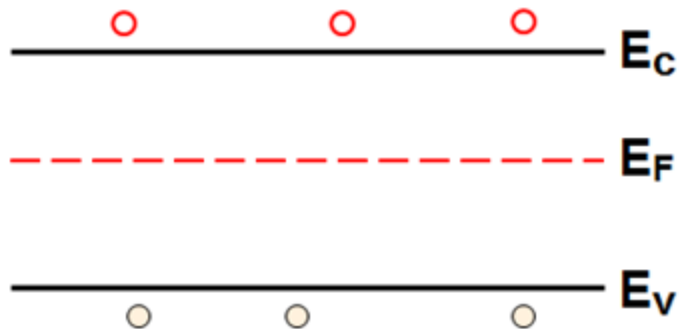
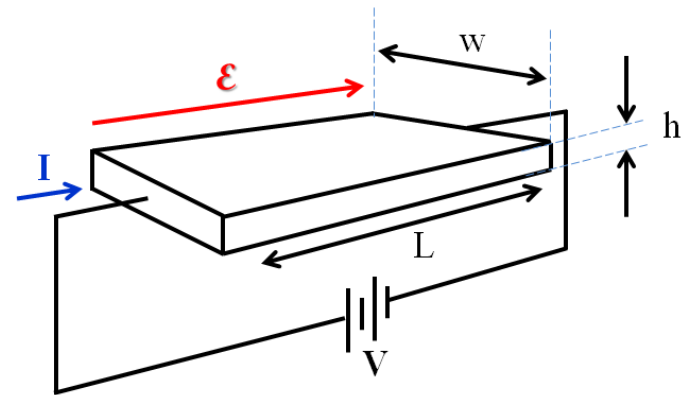
- **Optical absorption**
- **Excess carrier generation**
- **Direct Recombination of Electrons and Holes**
- **Steady State Carrier Generation**
- **Photoconductive Devices**
- **Quasi-Fermi Level**

The key to many semiconductor devices

- **Generate charge carriers in excess of thermal equilibrium values.**

Example: intrinsic Si

- $T = 300 \text{ K}$
- $n = n_i$
- $p = p_i$



What happens if we connect a battery at the ends of a bar made of intrinsic Si? (assume ohmic contacts)

$$V = 10 \text{ V}$$

$$L = 1.0 \text{ cm}$$

$$A = h \times w = 1.0 \text{ mm}^2$$

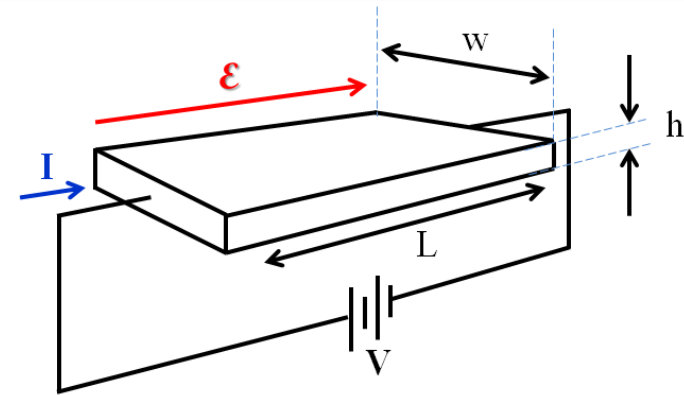
There is not much of a current

- **Resistivity**

$$\rho = \frac{1}{q\mu_n n_i + q\mu_p n_i} = \frac{1}{qn_i(\mu_n + \mu_p)} =$$
$$= \frac{1}{1.6 \times 10^{-19} \times 1.5 \times 10^{10} (1350 + 480)} = 227.4 \text{ k}\Omega \cdot \text{cm}$$

$$R = \rho \frac{L}{A} = 227.4 \times 10^3 \frac{1.0}{10^{-2}} = 22.74 \times 10^6 = 22.74 \text{ M}\Omega$$

$$I = \frac{V}{R} = \frac{10}{22.74 \times 10^6} = 0.44 \mu\text{A}$$



Can we increase the current somehow (i.e. increase carrier concentration)?

Some possible ways

We already know at least two ways:

- **Increase the temperature**
- **Introduce doping in the semiconductor to enhance free carriers (both imply increased scattering and lower mobility)**

These modalities do not introduce “excess carriers” but rely on establishing a new equilibrium condition

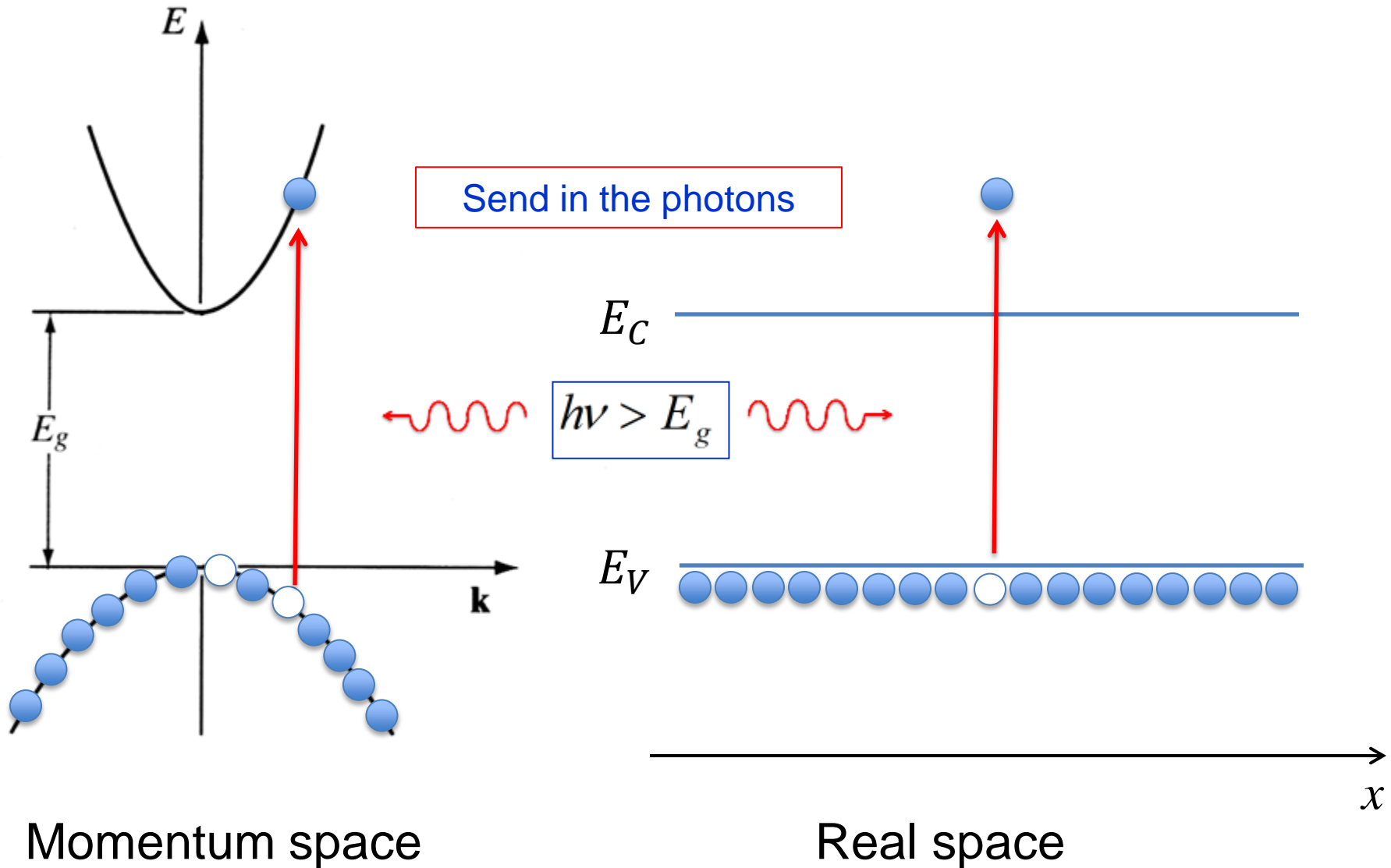
Shine EM waves (e.g., light) with photon Energy $>$ Band gap

Field Effect: accumulate carriers with a “capacitive” structure

Design a structure that injects carriers from one region to another

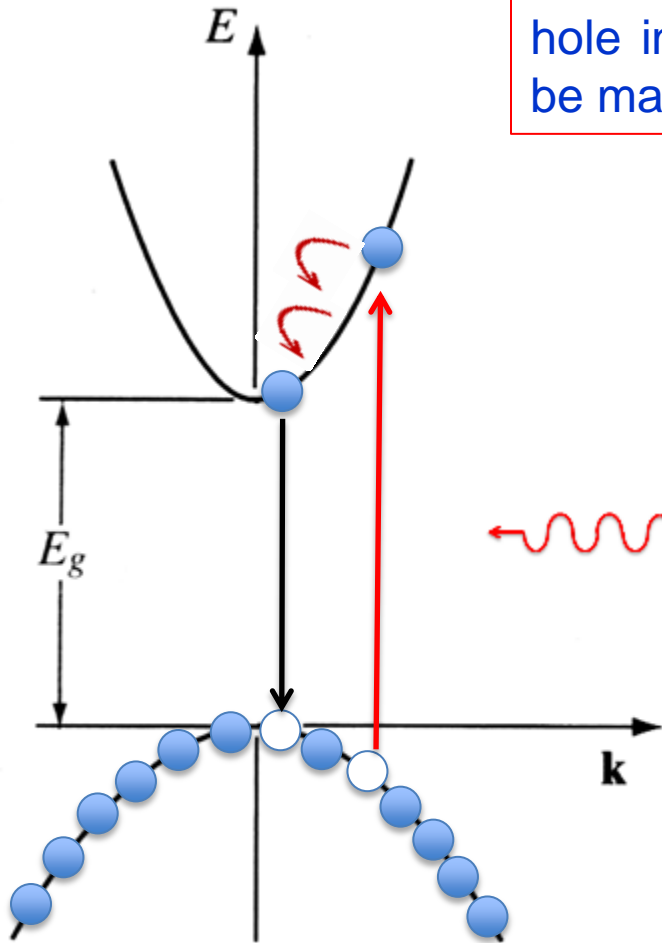
Design a structure that energizes free carriers to knock off a lot of electrons from the valence band (and corresponding hole creation) with an “avalanche” multiplication process (impact ionization)

Let's try light

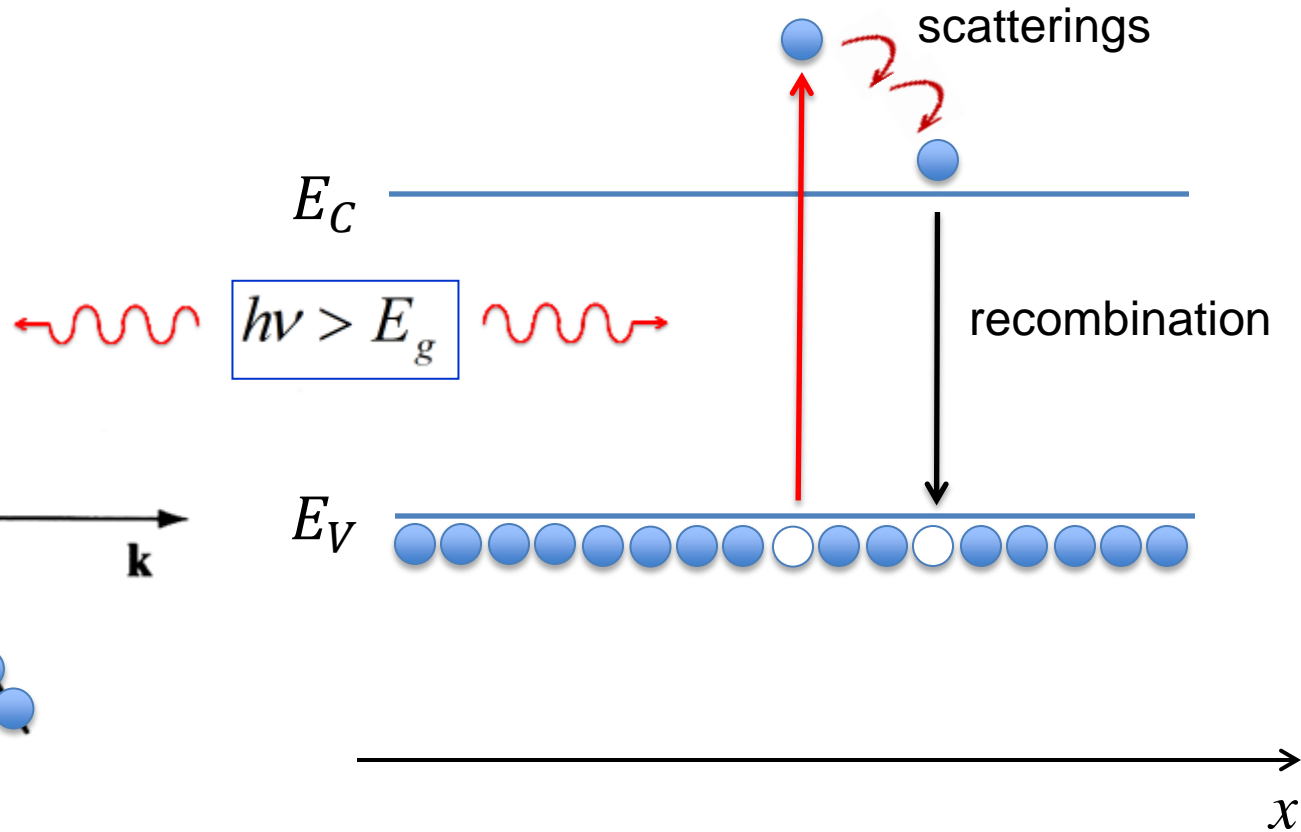


Let's try light

The excited electron will eventually recombine with a hole in valence band. A stable excess population can be maintained by pumping a suitable intensity of photons.

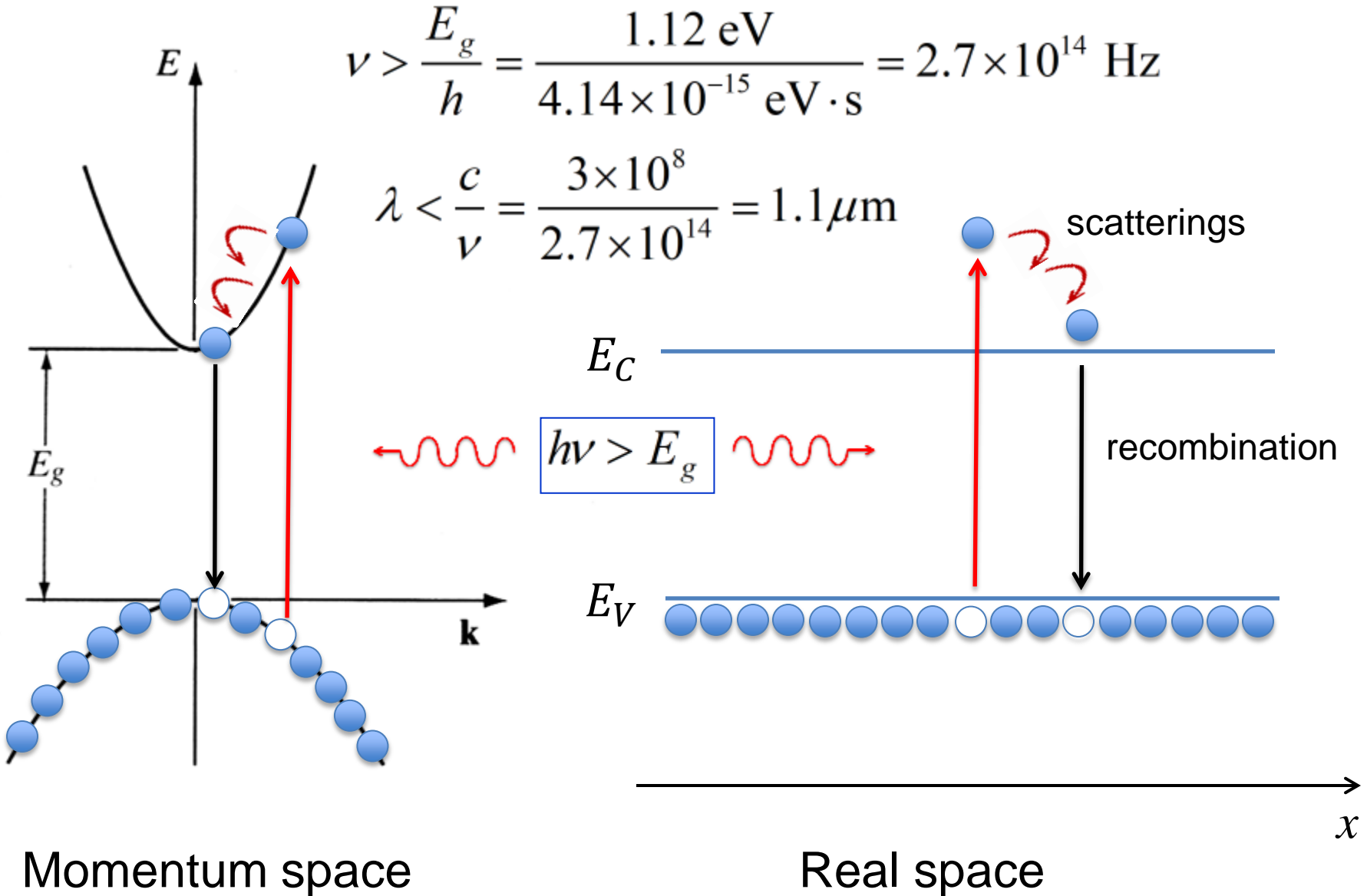


Momentum space



Real space

Let's try light



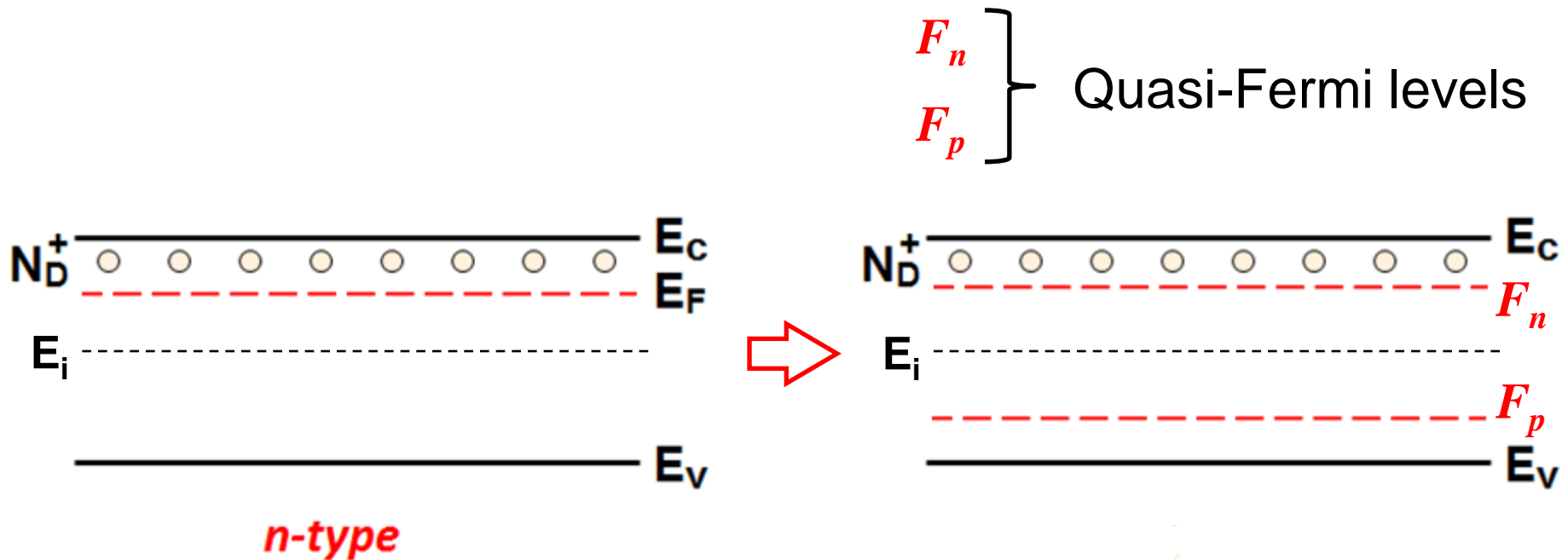
You can also use the handy formula

$$\lambda_0 = \frac{1.24}{E_g [\text{eV}]} = [\mu\text{m}] = \frac{1240}{E_g [\text{eV}]} [\text{nm}]$$

**Keep in mind that this formula is for
wavelength in vacuum**

But what happens to the Fermi Level?

If we generate excess carriers so that $\Delta n = \Delta p > n_0, p_0$



$$n_0 = n_i e^{(E_F - E_i)/kT}$$

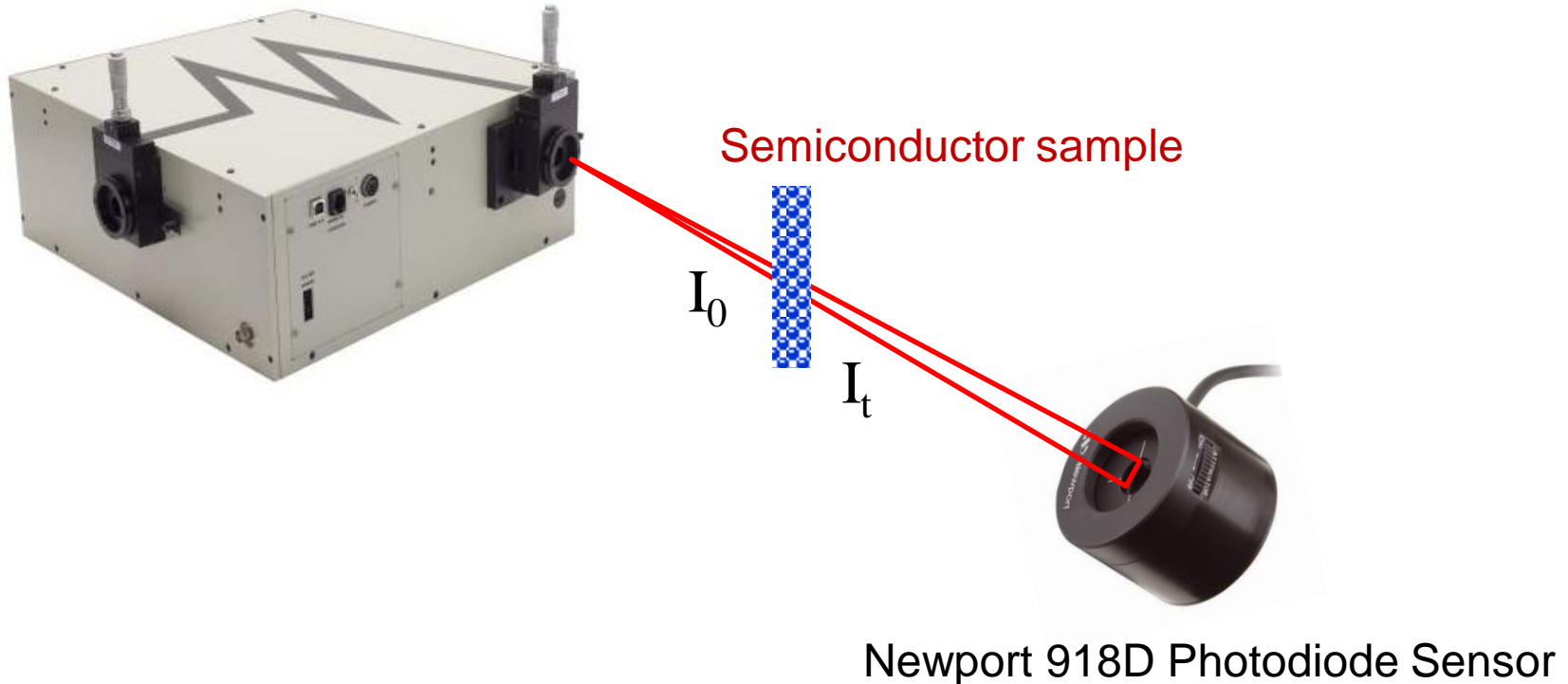
$$p_0 = n_i e^{(E_i - E_F)/kT}$$

$$n = n_i e^{(F_n - E_i)/kT}$$

$$p = n_i e^{(E_i - F_p)/kT}$$

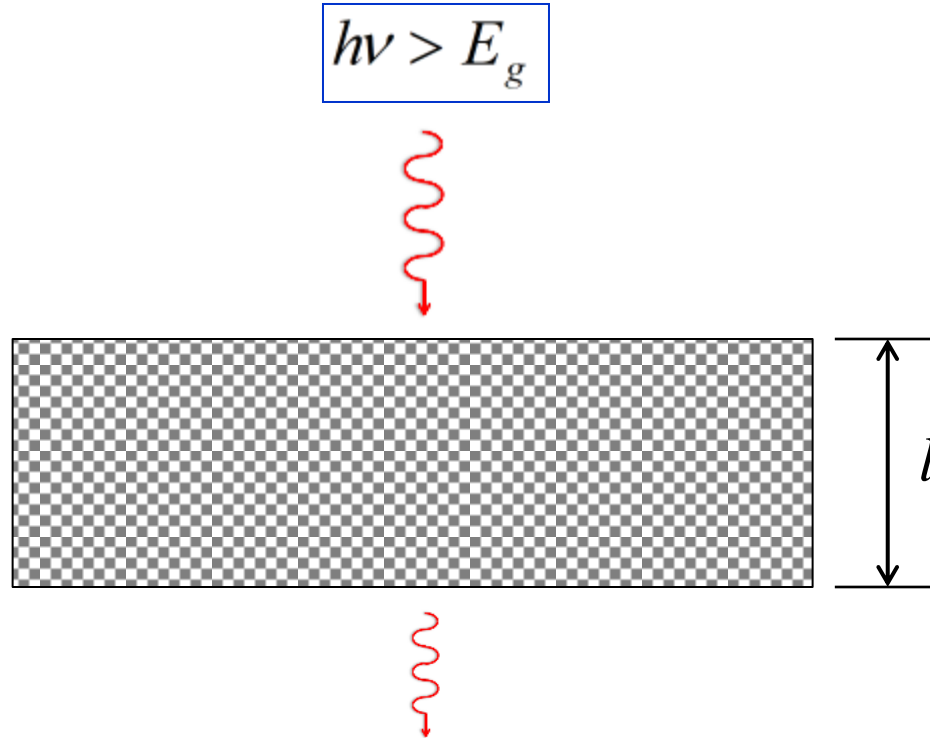
Optical Absorption

Newport CS260 Monochromator + wide spectrum lamp
Select frequency with diffraction gratings

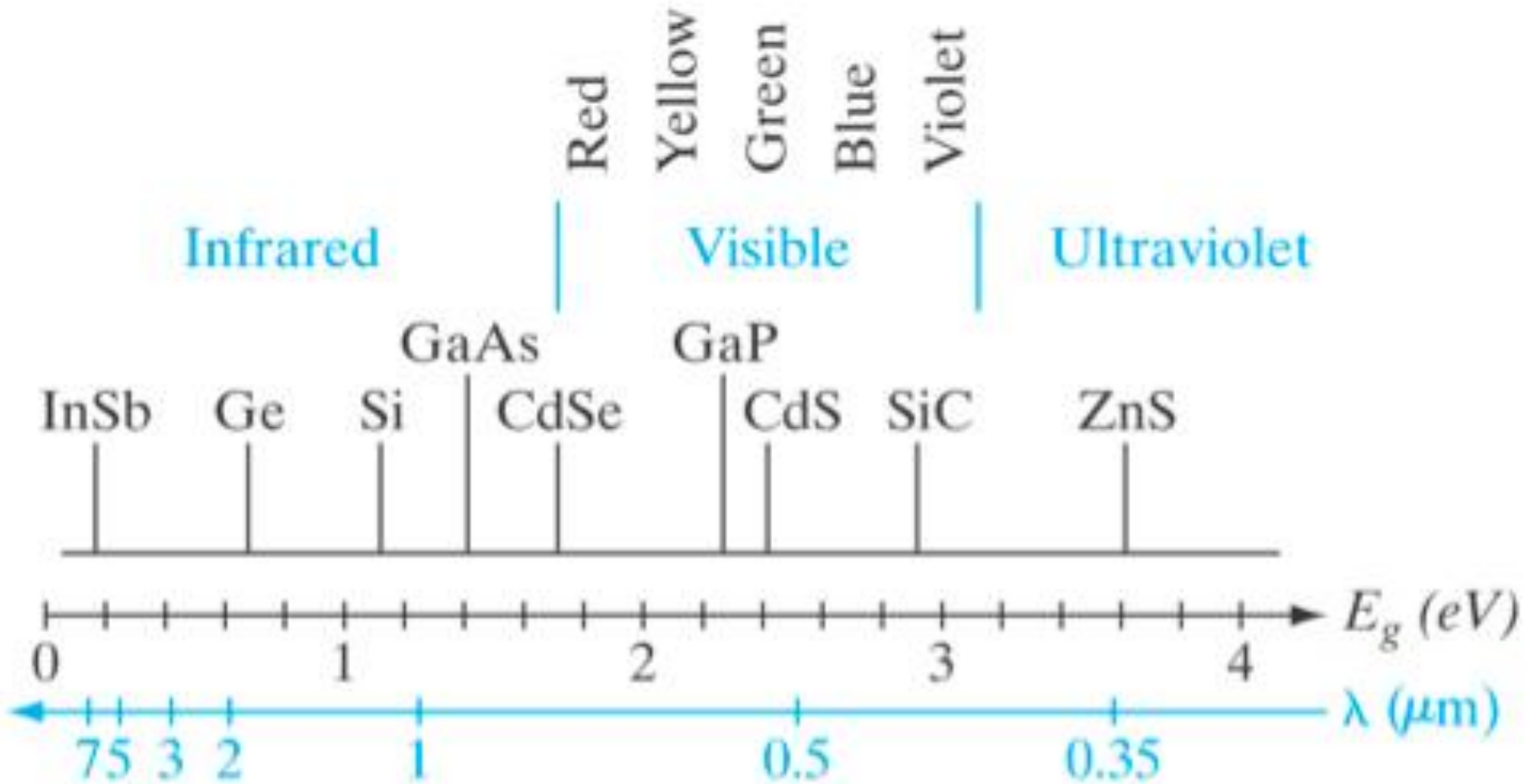


As the beam travels in the semiconductor it is absorbed at a rate proportional to the intensity

Optical Absorption



Wavelengths and band gaps

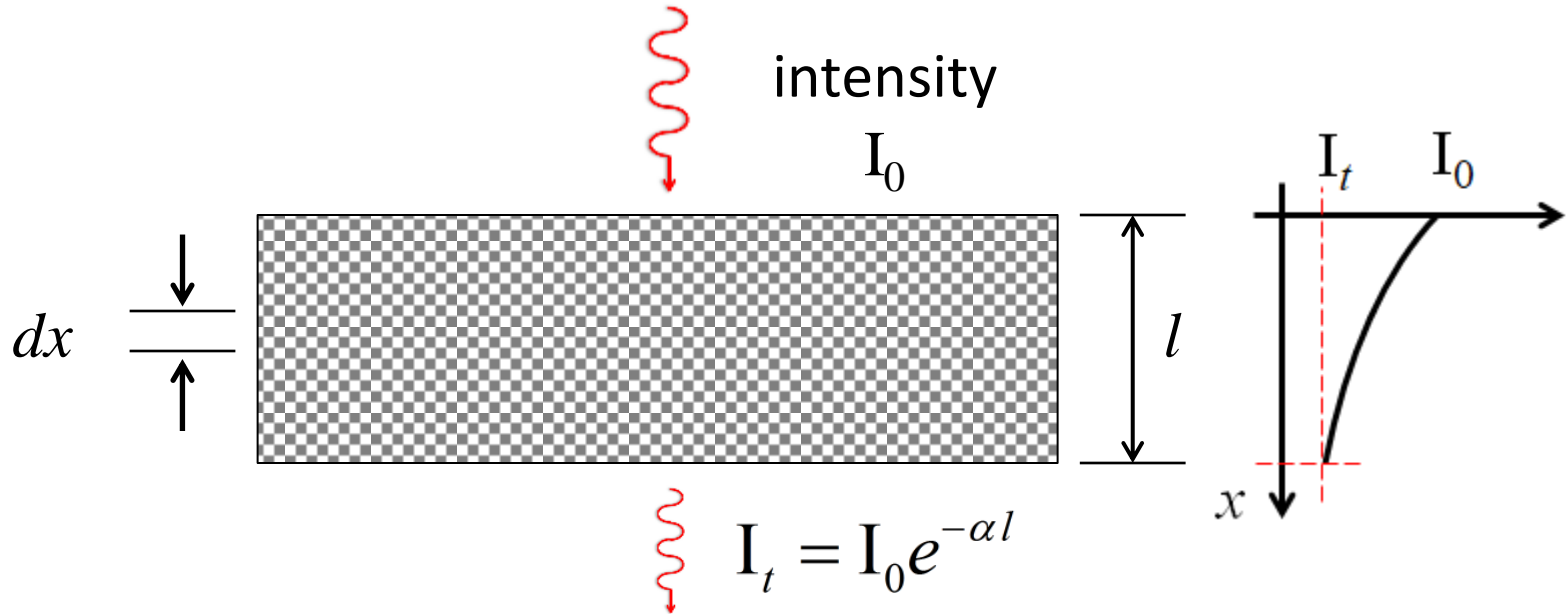


Optical Absorption

I_0 [photons/cm²-s]

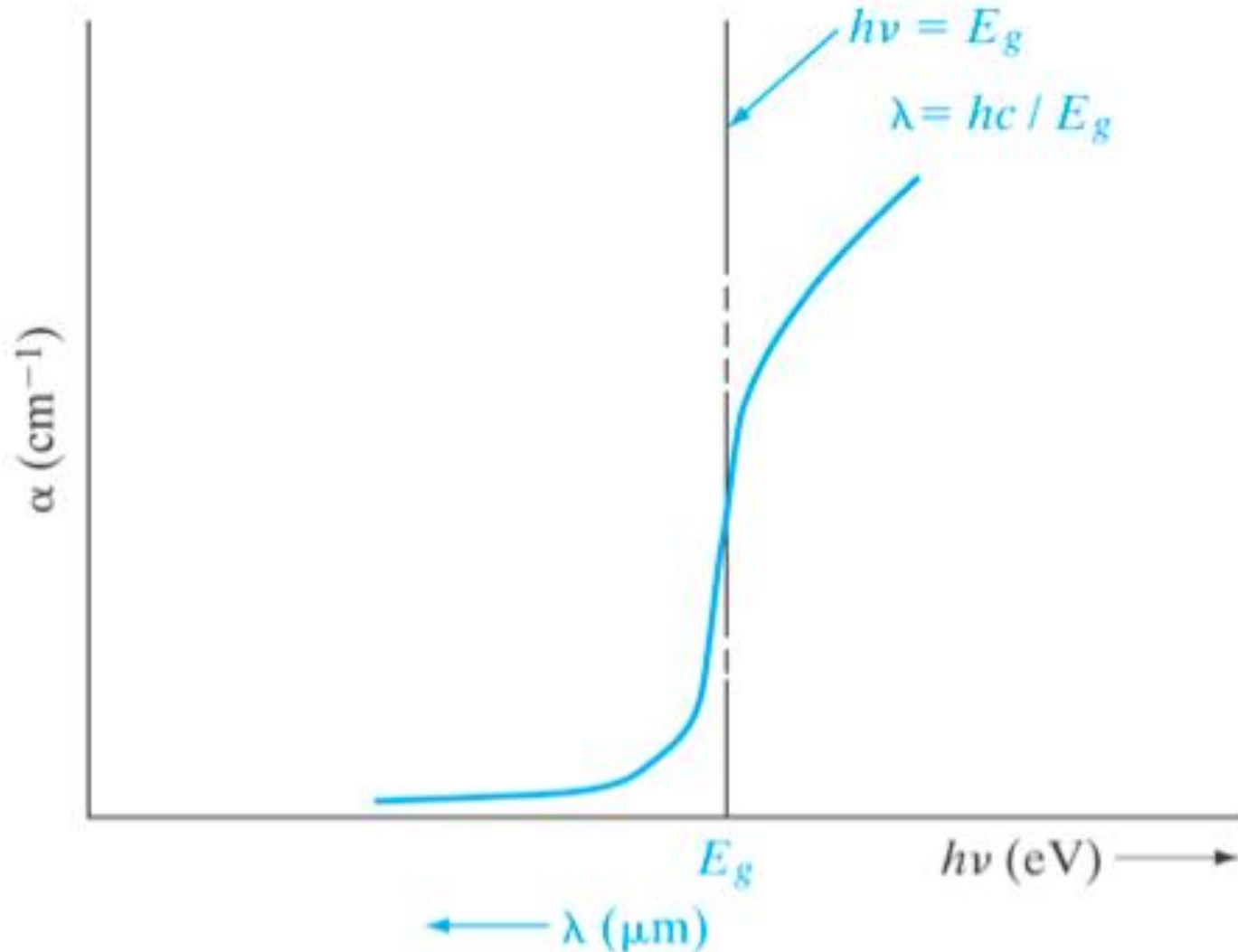
α = absorption coefficient

$$h\nu > E_g$$

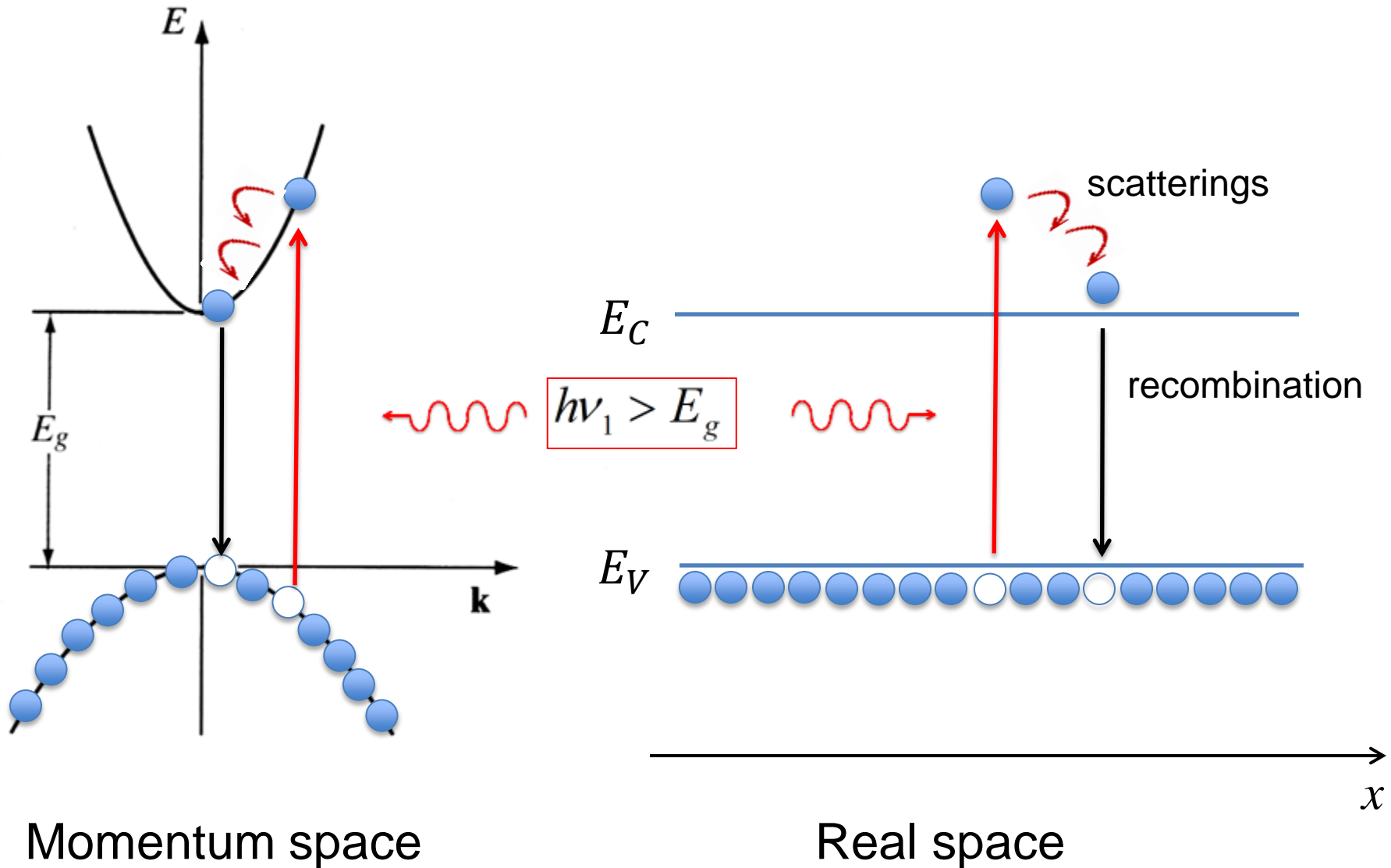


$$-\frac{d I(x)}{dx} = \alpha I(x) \quad \Rightarrow \quad I(x) = I_0 e^{-\alpha x}$$

Optical Absorption Coefficient

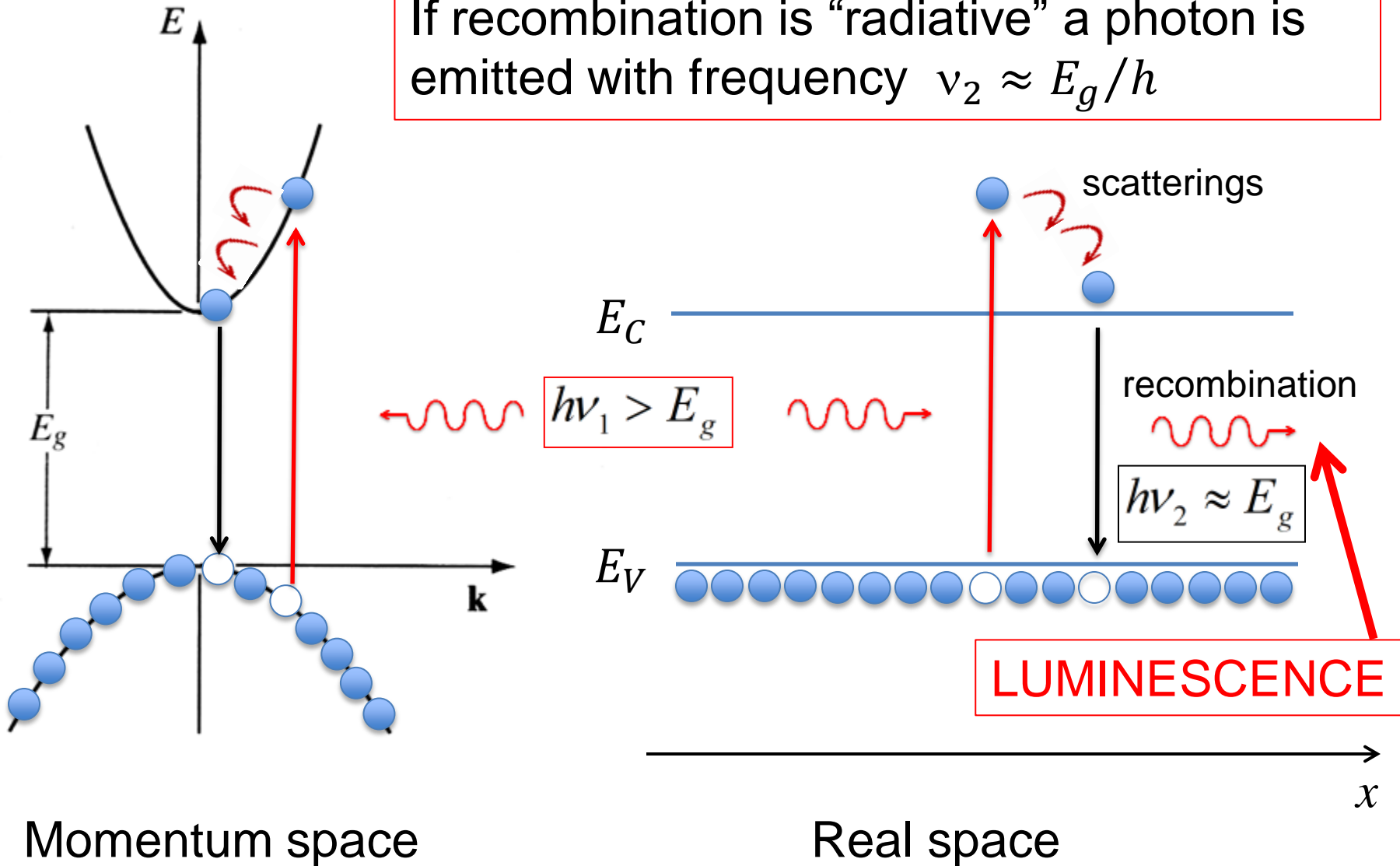


The competing process is recombination



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If recombination is “radiative” a photon is emitted with frequency $\nu_2 \approx E_g/h$



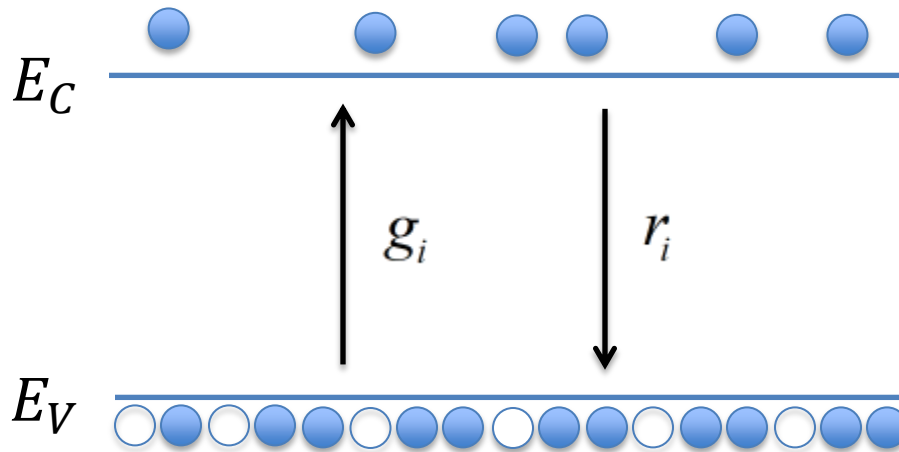
Recombination of Electrons and Holes

Thermal recombination rate = thermal generation rate

$$r_i = \alpha_r n_o p_o = \alpha_r n_i^2 = g_i$$

α_r is a proportionality constant that depends on the recombination mechanism

(**NOTE** – this is **NOT** the same as α = absorption coefficient)



Recombination of Electrons and Holes

In equilibrium

$$0 = \underbrace{\alpha_r n_i^2}_{\text{thermal generation}} - \underbrace{\alpha_r n_i^2}_{\text{recombination}} = \underbrace{\alpha_r n_i^2}_{\text{thermal generation}} - \underbrace{\alpha_r n_o p_o}_{\text{recombination}}$$

$$0 = \underbrace{\alpha_r n_o p_o}_{\text{thermal generation}} - \underbrace{\alpha_r n_o p_o}_{\text{recombination}}$$

Recombination of Electrons and Holes

$$h\nu > E_g$$



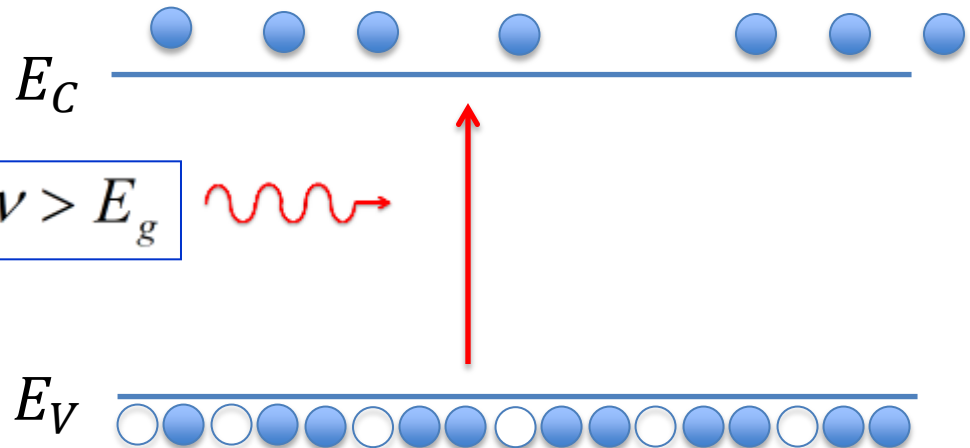
initial condition
for recombination

$$t = 0$$

$$\Delta n = \Delta p = \text{initial excess concentration}$$

Now we pump electrons into the conduction band by a short flash of light that ends at $t = 0$

$$h\nu > E_g$$



$\delta n(t)$ = instantaneous concentration of excess electrons

$\delta p(t)$ = instantaneous concentration of excess holes

Recombination of Electrons and Holes

If we generate excess carriers, the net rate of change of electrons in the conduction band is given by

$$\underbrace{\frac{dn(t)}{dt}}_{\text{net rate of change}} = \underbrace{\alpha_r n_i^2}_{\text{thermal generation rate}} - \underbrace{\alpha_r n(t) p(t)}_{\text{recombination rate}}$$

$$\frac{d[n_o + \delta n(t)]}{dt} = \underbrace{\alpha_r n_i^2}_{\text{thermal generation}} - \underbrace{\alpha_r [n_o + \delta n(t)][p_o + \delta p(t)]}_{\text{recombination}}$$

Recombination of Electrons and Holes

$$t = 0$$

$$\Delta n = \Delta p = \text{initial excess concentration}$$

$$\underbrace{\frac{dn(t)}{dt}}_{\text{net rate of change}} = \underbrace{\alpha_r n_i^2}_{\text{thermal generation rate}} - \underbrace{\alpha_r n(t)p(t)}_{\text{recombination rate}}$$

Electrons and holes recombine in pairs

$$\delta n(t) = \delta p(t)$$

$$\frac{d\delta n(t)}{dt} = \alpha_r n_i^2 - \alpha_r [n_o + \delta n(t)][p_o + \delta p(t)]$$

$$\frac{d\delta n(t)}{dt} = -\alpha_r [(n_o + p_o)\delta n(t) + \delta n^2(t)]$$

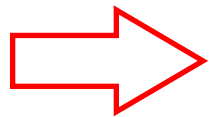
Use $n_o p_o = n_i^2$
to eliminate $\alpha_r n_i^2$

Low-level injection conditions → Simplification

$$\frac{d \delta n(t)}{d t} = -\alpha_r \left[(n_o + p_o) \delta n(t) + \underbrace{\delta n^2(t)}_{\text{can be neglected}} \right]$$

Extrinsic semiconductor p-type

$$\frac{d \delta n(t)}{d t} \simeq -\alpha_r p_o \delta n(t) \quad p_o \gg n_o \quad \text{Neglect equilibrium minority carriers}$$



$$\delta n(t) = \underbrace{\Delta n}_{\text{initial condition}} \exp(-\alpha_r p_o t) = \Delta n \exp\left(-\frac{t}{\tau_n}\right)$$

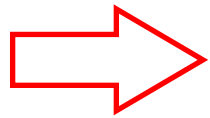
$$\tau_n = \frac{1}{\alpha_r p_o} = \text{minority recombination lifetime}$$

Low-level injection conditions → Simplification

$$\frac{d \delta n(t)}{d t} = -\alpha_r \left[(n_o + p_o) \delta n(t) + \underbrace{\delta n^2(t)}_{\text{can be neglected}} \right]$$

Extrinsic semiconductor *n*-type

$$\frac{d \delta p(t)}{d t} \simeq -\alpha_r n_o \delta p(t) \quad n_o \gg p_o \quad \text{Neglect equilibrium minority carriers}$$



$$\delta p(t) = \underbrace{\Delta p}_{\text{initial condition}} \exp(-\alpha_r n_o t) = \Delta p \exp\left(-\frac{t}{\tau_p}\right)$$

$$\tau_p = \frac{1}{\alpha_r n_o} = \text{minority recombination lifetime}$$

Low level injection conditions → Simplification

More generally you can use this formula

$$\tau = \frac{1}{\alpha_r (n_o + p_o)}$$

It works for both p - and n -type material in low level injection conditions